Appointment

From: Parsons, Doug [Parsons.Douglas@epa.gov]
Sent: 6/7/2021 7:38:28 PM
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Subject: Overview of Comments on NMP from National Electrical Manufacturers Association
Attachments: 2021-06-07 NEMA Comments on NMP_FINAL.pdf

Location: Microsoft Teams Meeting

Start: 6/29/2021 5:00:00 PM
End: 6/29/2021 6:00:00 PM
Show Time As: Tentative

Required Attendees: Parsons, Doug; Wolf, Joel; Kramek, Niva; Hull, Clara; Shuman, Amy; Brown, Judith; Popko, David; Wegner, Susanna; Suek, Nicholas; Luz, Anthony; Sheehan, Eileen; Tatman, Stacy

Optional Attendees: Aaron Brandt; Logsdon, Mike A; Smith, Christopher; Dan Isaksson; Rodger W Reiswig; Dolin, Jennifer; Dan Nachtigall; Philip Kaufman; Charles Decker; Zhou, Liming [ACIM/HVACR/STL]; Mike Madsen; Greg Corban; Shana Longo; Wait, Susan J; Fred. Sanford; Kent Crawford; Rejent, Kevin; Rachel Murnyack; Friedman, Robert; Larry Richards; Thompson, David; Hess, Christopher D; Distler, Robert J.; Spears, Robert; Nadigera, Kishan; Tesch, Todd E [COMRES/SID]; Carlson, Brian E; Borowski, Ron S; Solomon Chiang; Mirna Garza Gonzalez; Joe Caligiuri; Laymond Drummond; Jacques, Tom R; Richmond, David; Wel, Hans van der; Keith Waters; john.bermingham@fujifilm.com; Britton, Irina; Cretu, Dan; Pablo Sifuentes Barrera; Carrier, Mark [ACIM/HVACR/STL]; Stowe, Matt; Michael CHLEBOWSKI; Tuckwell, Stephen; Rachael Meyer; John Sheff; Houg, Eric (TIC); Caudill, Gregory S; Edgar Alberto Duarte Pena; George, Elisabeth; Donell P. Jackson; Abbate, Daniel; Patrick Salas; David Garza Herrera; Anthony Serres; Ryan Mayfield; David Stankes; Brent Ness; Andrew Dunn; Huesmann, Heinz; Mike Boivin; Mary Burgoon; Baroncini, Vincent; William Maher; Davis, Greg; aaron_meilahn@yaskawa.com; Srebnik, Laura; Oswald NiCole (BT-CO/ECS); jcarlock@fujifilm.com; Hull, Carolyn; Grace, John; Michell Coats; Morray, Boima; Neeser, Daniel R; Oldaker, Chuck; Christel Hunter; Hoffman, Evan; Sheila Quinnies; Squair, Philip; Valencia, Jose Ramon; Helms, Douglas; Parrish, Todd; Richard Field - PGR; Batra, Raj; John Taylor; Krug, Adam W; Mickael Lira De La Mora; Anderson, Kirk; Kevin Porter; Schertel John (BT-AI/PAI-ENG3); Neil Czarnecki; Marie Farmer; Majo Thurman; Siebenlist, John J; Mike Patel; Washington, Kevin; Guy Benjamin; jbrooks@fujifilm.com; Porter, Russell W; Bruce A. Desmond; Dick Jackman; Wicks, Roger C

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